# **IGBT**

This Insulated Gate Bipolar Transistor (IGBT) features a robust and cost effective Trench construction, and provides superior performance in demanding switching applications, offering both low on state voltage and minimal switching loss.

#### **Features**

- Low Saturation Voltage using Trench with Field Stop Technology
- Low Switching Loss Reduces System Power Dissipation
- Soft Fast Reverse Recovery Diode
- Optimized for High Speed Switching
- 5 µs Short-Circuit Capability
- These are Pb-Free Devices

#### **Typical Applications**

- Solar Inverters
- Uninterruptable Power Supply (UPS)

#### **ABSOLUTE MAXIMUM RATINGS**

Rating	Symbol	Value	Unit
Collector-emitter voltage	V <sub>CES</sub>	600	V
Collector current @ Tc = 25°C @ Tc = 100°C	I <sub>C</sub>	80 40	Α
Pulsed collector current, T <sub>pulse</sub> limited by T <sub>Jmax</sub>	I <sub>CM</sub>	160	Α
Diode Forward Current @ T <sub>C</sub> = 25°C @ T <sub>C</sub> = 100°C	I <sub>F</sub>	80 40	А
Diode Pulsed Current T <sub>pulse</sub> Limited by T <sub>Jmax</sub>	I <sub>FM</sub>	160	Α
Short–circuit withstand time $V_{GE}$ = 15 V, $V_{CE}$ = 300 V, $T_{J} \le +150^{\circ}C$	t <sub>SC</sub>	5	μs
Gate-emitter voltage Transient Gate Emitter Voltage (t <sub>p</sub> = 5 μs, D < 0.010)	V <sub>GE</sub>	±20 ±30	٧
Power Dissipation @ Tc = 25°C @ Tc = 100°C	P <sub>D</sub>	257 102	W
Operating junction temperature range	TJ	–55 to +150	°C
Storage temperature range	T <sub>stg</sub>	-55 to +150	°C
Lead temperature for soldering, 1/8" from case for 5 seconds	T <sub>SLD</sub>	260	°C

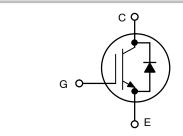
Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

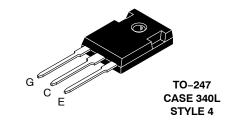


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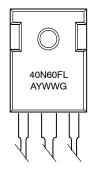
http://onsemi.com

40 A, 600 V **V<sub>CEsat</sub>** = 1.85 **V** 





#### **MARKING DIAGRAM**



= Assembly Location Α

= Year WW = Work Week = Pb-Free Package

## **ORDERING INFORMATION**

Device	Package	Shipping
NGTB40N60FLWG	TO-247 (Pb-Free)	30 Units / Rail

## THERMAL CHARACTERISTICS

Rating	Symbol	Value	Unit
Thermal resistance junction-to-case, for IGBT	$R_{ heta JC}$	0.470	°C/W
Thermal resistance junction-to-case, for Diode	$R_{ heta JC}$	1.06	°C/W
Thermal resistance junction-to-ambient	$R_{ hetaJA}$	40	°C/W

## **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
STATIC CHARACTERISTIC	•	•				
Collector-emitter breakdown voltage, gate-emitter short-circuited	$V_{GE} = 0 \text{ V}, I_{C} = 500 \mu\text{A}$	V <sub>(BR)CES</sub>	600	-	-	V
Collector-emitter saturation voltage	V <sub>GE</sub> = 15 V, I <sub>C</sub> = 40 A V <sub>GE</sub> = 15 V, I <sub>C</sub> = 40 A, T <sub>J</sub> = 150°C	V <sub>CEsat</sub>	1.6 -	1.85 2.3	2.1 -	V
Gate-emitter threshold voltage	$V_{GE} = V_{CE}, I_{C} = 200 \mu A$	$V_{GE(th)}$	4.5	5.5	6.5	V
Collector-emitter cut-off current, gate- emitter short-circuited	V <sub>GE</sub> = 0 V, V <sub>CE</sub> = 600 V V <sub>GE</sub> = 0 V, V <sub>CE</sub> = 600 V, T <sub>J</sub> = 150°C	I <sub>CES</sub>	<del>-</del>	- -	0.2 2	mA
Gate leakage current, collector-emitter short-circuited	V <sub>GE</sub> = 20 V , V <sub>CE</sub> = 0 V	I <sub>GES</sub>	_	-	100	nA
DYNAMIC CHARACTERISTIC	•	•		•		
Input capacitance		C <sub>ies</sub>	-	4200	-	pF
Output capacitance	$V_{CE} = 20 \text{ V}, V_{GE} = 0 \text{ V}, f = 1 \text{ MHz}$	C <sub>oes</sub>	-	170	-	
Reverse transfer capacitance	1	C <sub>res</sub>	_	110	-	
Gate charge total		$Q_g$	_	171	-	nC
Gate to emitter charge	$V_{CE}$ = 480 V, $I_{C}$ = 40 A, $V_{GE}$ = 15 V	Q <sub>ge</sub>	_	36	-	
Gate to collector charge		Q <sub>gc</sub>	-	83	-	
SWITCHING CHARACTERISTIC, INDUC	TIVE LOAD	•		•		•
Turn-on delay time		t <sub>d(on)</sub>	-	85	-	ns
Rise time	1	t <sub>r</sub>	-	37	-	
Turn-off delay time	T <sub>J</sub> = 25°C	t <sub>d(off)</sub>	-	174	-	
Fall time	$V_{CC} = 400 \text{ V}, I_{C} = 40 \text{ A}$ $R_{g} = 10 \Omega$	t <sub>f</sub>	-	73	-	
Turn-on switching loss	$V_{GE} = 0 \text{ V} / 15 \text{ V}$	E <sub>on</sub>	-	0.89	-	mJ
Turn-off switching loss	1	E <sub>off</sub>	_	0.44	-	
Total switching loss		E <sub>ts</sub>	-	1.33	-	
Turn-on delay time		t <sub>d(on)</sub>	-	82	-	ns
Rise time		t <sub>r</sub>	-	38	-	
Turn-off delay time	T <sub>J</sub> = 150°C	t <sub>d(off)</sub>	-	179	-	
Fall time	$V_{CC} = 400 \text{ V}, I_{C} = 40 \text{ A}$	t <sub>f</sub>	-	95	-	
Turn-on switching loss	$R_g = 10 \Omega$ $V_{GE} = 0 \text{ V} / 15 \text{ V}$	E <sub>on</sub>	-	1.10	-	mJ
Turn-off switching loss		E <sub>off</sub>	-	0.84	-	1
Total switching loss	7	E <sub>ts</sub>	_	1.94	-	

# **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
DIODE CHARACTERISTIC	DIODE CHARACTERISTIC					
Forward voltage	V <sub>GE</sub> = 0 V, I <sub>F</sub> = 40 A V <sub>GE</sub> = 0 V, I <sub>F</sub> = 40 A, T <sub>J</sub> = 150°C	V <sub>F</sub>	1.55 -	2.2 2.3	2.60	V
Reverse recovery time	T <sub>.I</sub> = 25°C	t <sub>rr</sub>	-	77	-	ns
Reverse recovery charge	$I_F = 40 \text{ Å}, V_R = 200 \text{ V}$	Q <sub>rr</sub>	-	0.35	-	μC
Reverse recovery current	di <sub>F</sub> /dt = 200 A/μs	I <sub>rrm</sub>	-	7	-	Α

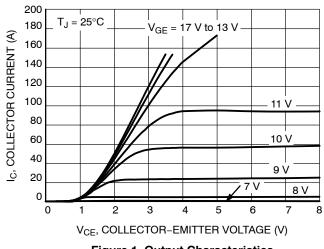


Figure 1. Output Characteristics

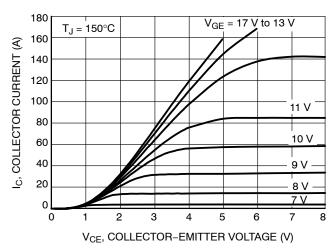


Figure 2. Output Characteristics

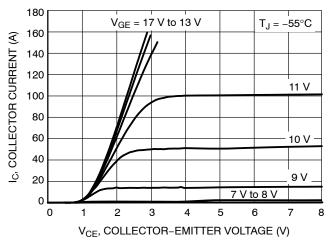


Figure 3. Output Characteristics

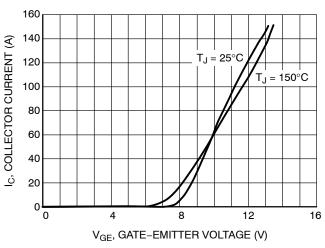


Figure 4. Typical Transfer Characteristics

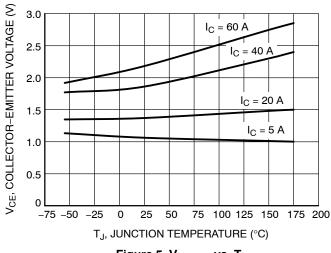


Figure 5.  $V_{CE(sat)}$  vs.  $T_J$ 

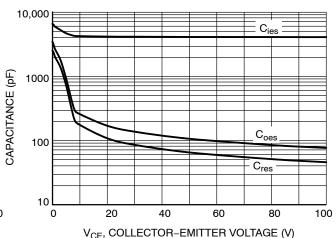


Figure 6. Typical Capacitance

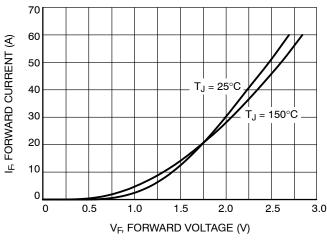


Figure 7. Diode Forward Characteristics

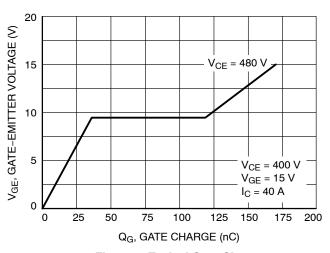


Figure 8. Typical Gate Charge

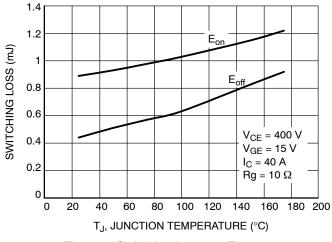


Figure 9. Switching Loss vs. Temperature

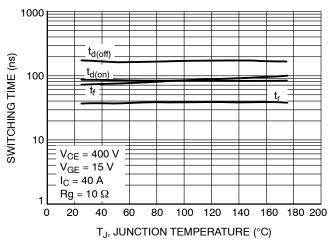


Figure 10. Switching Time vs. Temperature

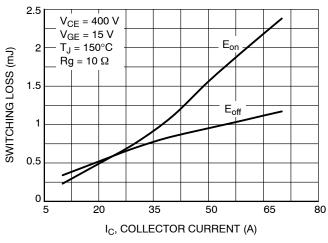


Figure 11. Switching Loss vs. I<sub>C</sub>

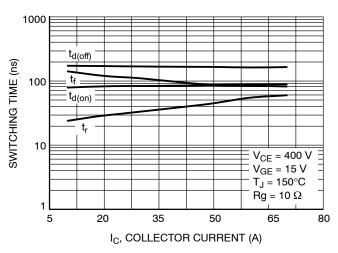
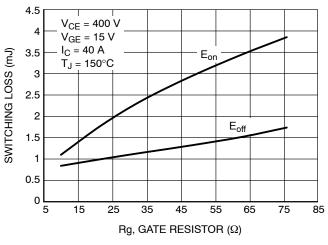


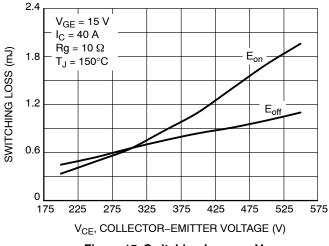
Figure 12. Switching Time vs. I<sub>C</sub>



1000 t<sub>d(off)</sub> t<sub>d(on)</sub> SWITCHING TIME (ns) 100 10 V<sub>CE</sub> = 400 V  $V_{GE}^{-} = 15 \text{ V}$ I<sub>C</sub> = 40 A T<sub>J</sub> = 150°C 5 15 25 35 45 65 Rg, GATE RESISTOR  $(\Omega)$ 

Figure 13. Switching Loss vs. Rg

Figure 14. Switching Time vs. Rg



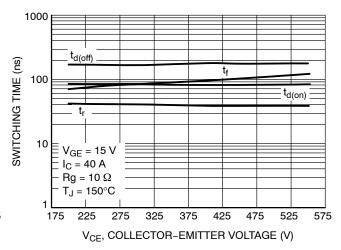
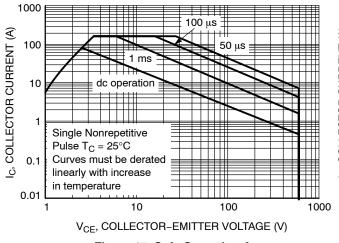


Figure 15. Switching Loss vs. V<sub>CE</sub>

Figure 16. Switching Time vs.  $V_{CE}$ 



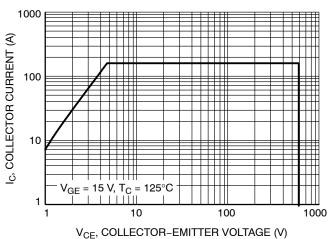


Figure 17. Safe Operating Area

Figure 18. Reverse Bias Safe Operating Area

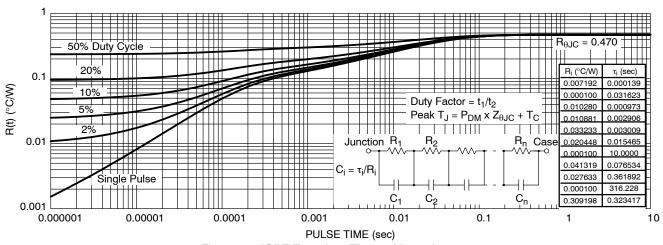


Figure 19. IGBT Transient Thermal Impedance

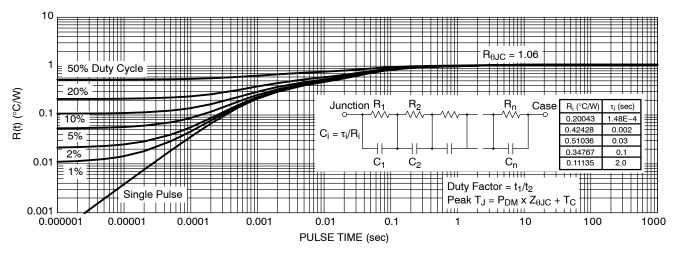


Figure 20. Diode Transient Thermal Impedance

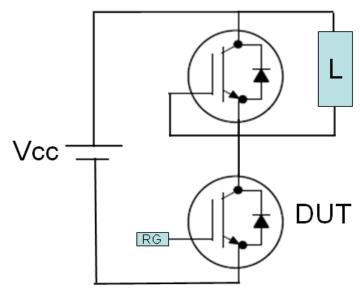
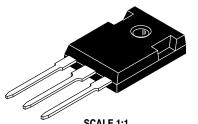
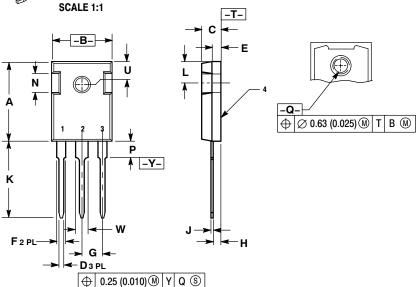


Figure 21. Test Circuit for Switching Characteristics



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**DATE 26 OCT 2011** 



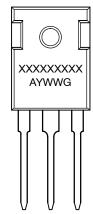
STYLE 2: PIN 1. ANODE 2. CATHODE (S) STYLE 4:
PIN 1. GATE
2. COLLECTOR
3. EMITTER
4. COLLECTOR STYLE 1: PIN 1. GATE 2. DRAIN STYLE 3: PIN 1. BASE 2. COLLECTOR 3. SOURCE 4. DRAIN 3. ANODE 2 4. CATHODES (S) 3. EMITTER 4. COLLECTOR STYLE 5: PIN 1. CATHODE 2. ANODE 3. GATE 4. ANODE STYLE 6: PIN 1. MAIN TERMINAL 1 2. MAIN TERMINAL 2

3. GATE 4. MAIN TERMINAL 2

- NOTES:
  1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
  2. CONTROLLING DIMENSION: MILLIMETER.

	MILLIMETERS		INC	HES
DIM	MIN	MAX	MIN	MAX
Α	20.32	21.08	0.800	8.30
В	15.75	16.26	0.620	0.640
С	4.70	5.30	0.185	0.209
D	1.00	1.40	0.040	0.055
Е	1.90	2.60	0.075	0.102
F	1.65	2.13	0.065	0.084
G	5.45 BSC		0.215 BSC	
Н	1.50	2.49	0.059	0.098
J	0.40	0.80	0.016	0.031
K	19.81	20.83	0.780	0.820
L	5.40	6.20	0.212	0.244
N	4.32	5.49	0.170	0.216
P		4.50		0.177
Q	3.55	3.65	0.140	0.144
U	6.15 BSC		0.242	BSC
W	2.87	3.12	0.113	0.123

#### **GENERIC MARKING DIAGRAM\***



XXXXX = Specific Device Code = Assembly Location

Υ = Year WW = Work Week G = Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present.

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98ASB15080	С

PAGE 2 OF 2

ISSUE	REVISION	DATE
D	CHANGE OF OWNERSHIP FROM MOTOROLA TO ON SEMICONDUCTOR. DIM A WAS 20.80-21.46/0.819-0.845. DIM K WAS 19.81-20.32/0.780-0.800. UPDATED STYLE 1, ADDED STYLES 2, 3, & 4. REQ. BY L. HAYES.	25 AUG 2000
E	DIM E MINIMUM WAS 2.20/0.087. DIM K MINIMUM WAS 20.06/0.790. ADDED GENERIC MARKING DIAGRAM. REQ. BY S. ALLEN.	26 FEB 2010
F	ADDED STYLES 5 AND 6. REQ. BY J. PEREZ.	26 OCT 2011

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